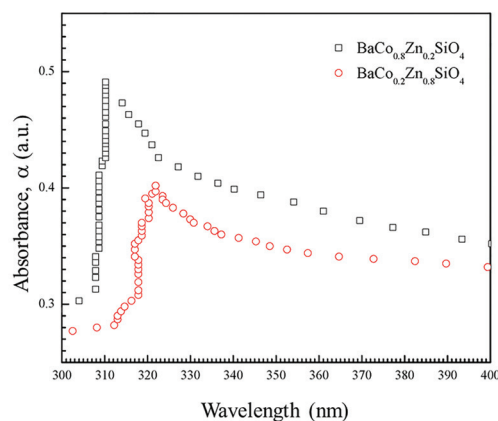
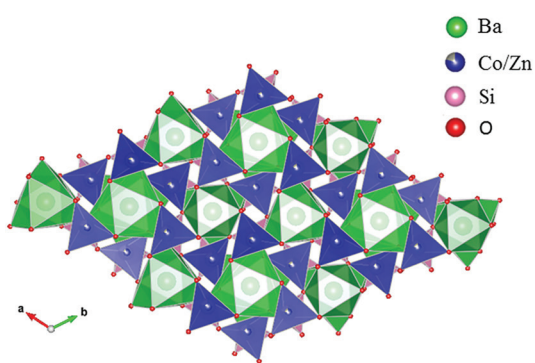
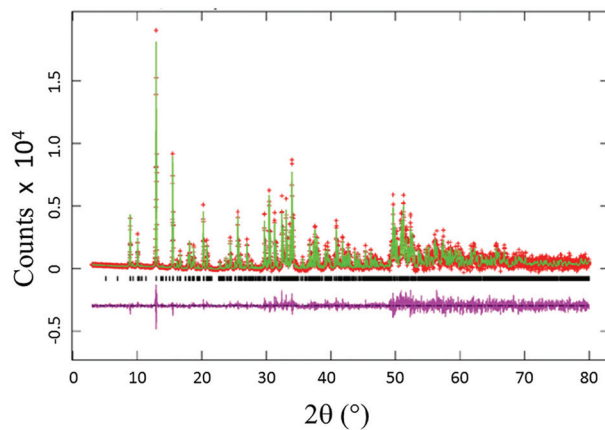


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Powder Diffraction

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Editor-in-Chief

Camden Hubbard
Applied Diffraction Services, U.S.A.
camden.hubbard@me.com

Managing Editor

Nicole M. Ernst Boris
International Centre for Diffraction Data, U.S.A.
boris@icdd.com

Production Editor

Kayla Riddleberger
Cambridge University Press, U.S.A.
kriddleberger@cambridge.org

Editors for New Diffraction Data

Soorya Kabekkodu
International Centre for Diffraction Data, U.S.A.
kabekkodu@icdd.com

Stacy Gates-Rector
International Centre for Diffraction Data, U.S.A.
gates-rector@icdd.com

Associate Editor for New Diffraction Data

Frank J. Rotella
Argonne National Laboratory (Retired), U.S.A.
fjrotella1949@gmail.com

Editors

Xiaolong Chen
Institute of Physics, Chinese Academy of Sciences, China
xlchen@iphy.ac.cn

José Miguel Delgado
Universidad de Los Andes, Venezuela
miguel@ula.ve

Norberto Masciocchi
Università dell'Insubria, Italy
norberto.masciocchi@uninsubria.it

Editors for Crystallography Education

James Kaduk
Poly Crystallography Inc., U.S.A.
Kaduk@polycrystallography.com

Brian H. Toby
Argonne National Laboratory, U.S.A.
brian.toby@anl.gov

International Reports Editor

Winnie Wong-Ng
National Institute of Standards and Technology, U.S.A.
winnie.wong-ng@nist.gov

Calendar of Meetings and Workshops Editor

Gang Wang
Institute of Physics, Chinese Academy of Sciences, China
gangwang@iphy.ac.cn

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On the Cover: Photocatalytic water splitting materials are being searched for use in production of clean burning hydrogen. In this issue of Powder Diffraction the paper "Structural and Optical Properties of $\text{Ba}(\text{Co}_{1-x}\text{Zn}_x)\text{SiO}_4$ ($x = 0.2, 0.4, 0.6, 0.8$)" by J. Anike, R. Derbeshi, W. Wong-Ng, W. Liu, D. Windover, N. King, S. Wang and J. Kaduk, the title compounds were characterized for both their powder diffraction patterns and their UV-Visible spectra. The cover figure shows the powder diffraction pattern for one of the members of the solid solution series along with the crystal structure showing the corner-shared $(\text{Co,Zn})\text{O}_4$ tetrahedra and the UV-visible absorption spectra of the as-synthesized and as suspended in water.

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